

S/N 10/063,295
Docket: BUR920010127US1

Image
2817



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of
Abadeer et al.

Serial No.: 10/063,295

Group Art Unit: 2817

Filed: April 9, 2002

Examiner: Shingleton, M.

For: SYSTEM AND METHOD FOR MEASURING CIRCUIT PERFORMANCE
DEGRADATION DUE TO PFET NEGATIVE BIAS TEMPERATURE
INSTABILITY (NBTI)

Commissioner for Patents
Alexandria, Virginia 22313-1450

AMENDMENT UNDER 37 C.F.R. §1.111

Sir:

In response to the Office Action dated July 21, 2003, please amend the
above-identified application as follows: